

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1542	382/141.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 08:37
L2	582	382/141.ccls. and threshold\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 08:37
L3	45	382/141.ccls. and.threshold\$4 with upper	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 08:38
L4	294	382/141.ccls. and threshold\$4 with (upper or zone or bound\$4 or region or area or sector)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 08:39
L5	106	382/141.ccls. and threshold\$4 with (upper or zone or bound\$4 or region or area or sector)same (defect or anomal\$4 or aberration)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 08:41
L6	89	382/141.ccls. and threshold\$4 with (upper or zone or bound\$4 or region or area or sector)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:04
L7	9	382/141.ccls. and threshold\$4 with (negative or positive or sign or polarity)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:02

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L8	57	382/141.ccls. and threshold\$4 with (upper or lower or second)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:08
L9	40	382/141.ccls. and threshold\$4 with (upper or lower)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:10
L10	0	382/141.ccls. and threshold\$4 with (upper or lower)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:10
L11	14	382/141.ccls. and threshold\$4 with (upper or lower)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:21
L12	134	threshold\$4 with (upper or lower)same (defect or anomal\$4 or aberration) and (differen\$4 or subtract\$4) with image and wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/12/18 09:21


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Machine Learning and Cybernetics, 2007 International Conference on
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Cho, T.-H.; Conners, R.W.; Araman, P.A.;
Pattern Recognition, 1990. Proceedings., 10th International Conference on
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Control and Automation, 2003. ICCA 2003. The Fourth International Conference on
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